Finishing Up

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Timeline

- 04/23: IHP expected to update DRC (stay tuned...)
- 04/26: Pull request (preliminary files)
- 04/29: Team updates: 2, 5, 6
- 05/01: Team updates: 1, 3, 4
- 05/03: Pull request ("final" files)
- 05/22: GDS deadline

Pull Request Contents

EE628/5_Design/4_Layout/Team X

TeamX.oas → Top level layout, contains all layout cells

TeamX.spice → Top level spice netlist

TeamX.sym → Top level symbol

TeamX.readme → Pin list + any notes you want to convey

TeamX_logo.oas → In case you want to include a logo

Please submit preliminary versions of all these files by 4/26

TeamX.readme Example

TeamX pin list:

```
Name Type Purpose

vin input Analog input of ADC

dout output Digital output of ADC

res input Digital rese signal (active high)

avdd supply Analog supply voltage
```

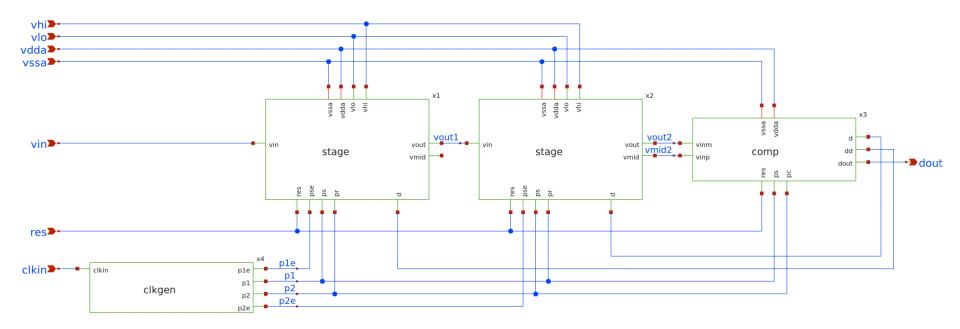
Current status:

These are the final files

Block Schematic

- Create both netlist and symbol form this schematic
 - Make sure there are no ideal spice elements!

p1: Stage 1 samples, stage 2 redistributes, comparator samples, dd toggles (used by stage 1 during p2) p2: Stage 2 samples, stage 1 redistributes, comparator decides, d toggles (used by stage 2 during p1)



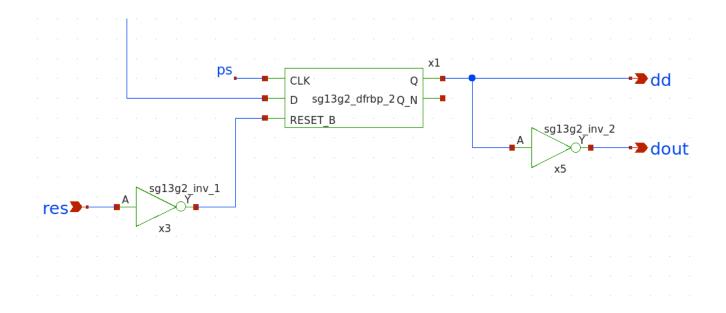


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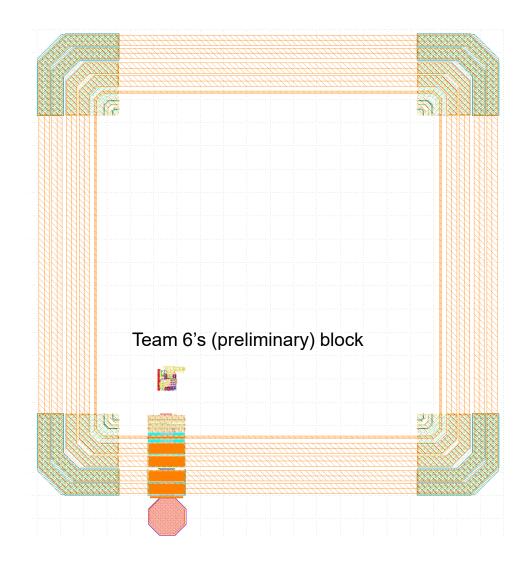
2024-04-22 22:13:22

/foss/designs/EE628/5_Design/3_Real_circuits/IDSM2.sch

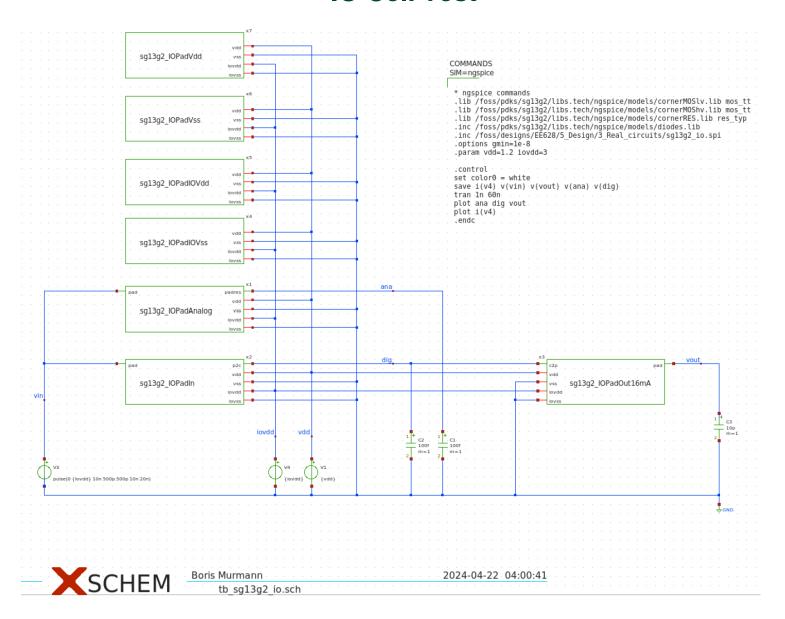
Recommended Output Signal (dout)



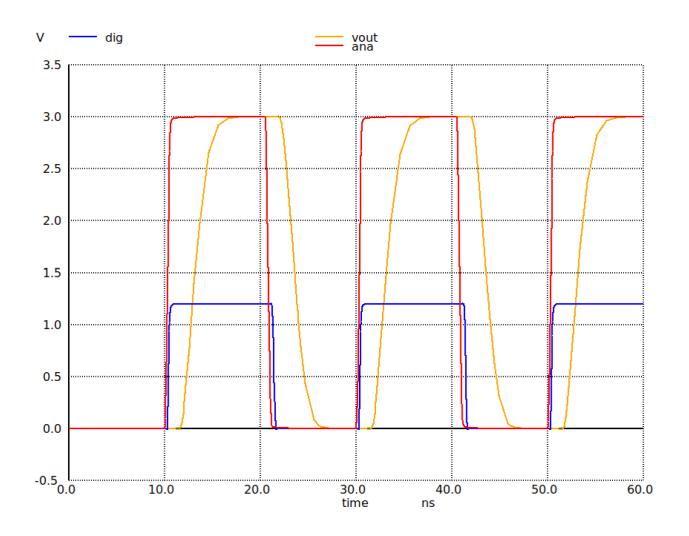
Preview of Chip Layout



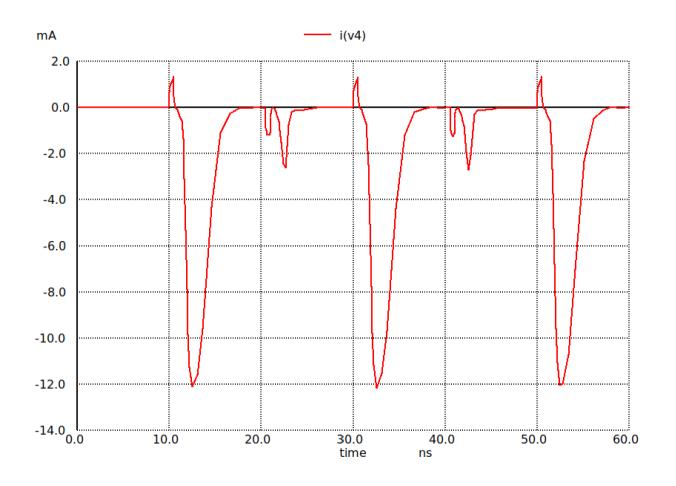
IO Cell Test



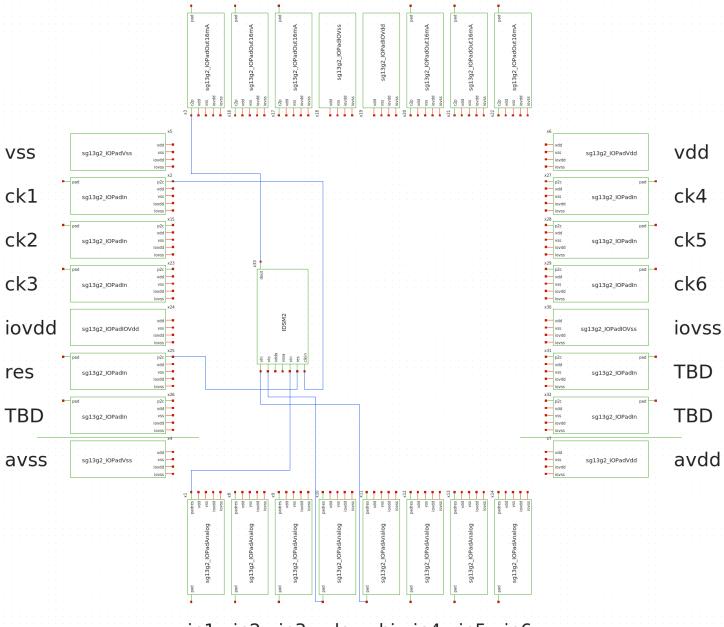
Voltage Waveforms



Digital Drive Current (VDDIO = 3V)



out1 out2 out3 iovss iovdd out4 out5 out6



in1 in2 in3 vlo vhi in4 in5 in6



Possible Outline for Next Week's Presentations

- What is your status?
 - What have you done since the last presentation?
 - What remains to be done?
 - What problems are you facing?
- What does your final block look like?
 - Top level schematic, pins, layout
- What have you done to check that your schematic and layout are correct?
 - Which simulations, corners?
 - How did you ensure that your layout has all the required connections?
 - In absence of LVS...

Guidelines for a Full Design Review Presentation

Design overview

- Walk through the system block diagram, give a big picture overview of the full system, clearly explain what is the input and what is the output
- Show the datapath/circuit diagram of each sub-block, explain how it works
- Talk about design decisions you made and the rationale behind them, explain the tradeoffs
- Verification of each sub-block and the entire system
 - Spice simulations, which tests did you perform?
 - How did you generate the stimuli?
 - What portions of the design are untested and what is your plan for testing them?

Initial results

- Estimate all design specific metrics you care about from spice simulation.
- How do these compare with your initial specification?
- If any devices other than MOSFETs are used, provide simulation plots showing extracted characteristics and describe the test setup.

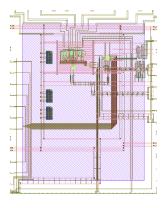
Integration

- What is the approximate area of the entire circuit
- Provide details regarding metals used for signal routing, power routing, layout methodology adopted for devices other than MOSFETs (Capacitor, Resistor, etc.)
- I/O pin details: How many analog I/O pins, digital I/O pins, VDD, VSS pins are required?

Plan for the remaining weeks

- Particularly talk about your layout strategy
- Provide a schedule with all milestones that you still need to complete for successful tapeout

Design review example: https://priyanka-raina.github.io/ee372-spring2022/



12-bit 10-KSPS Incremental Delta-Sigma ADC in Skywater 130 nm

Raymond Yang, Yaqing Xia

Code: Design, Caravel User Projectionalog

Documentation: Proposal, Design Review, Final Presentation, Report This project is a 12-bit 10 KSPS incremental delta-sigma analog-to-digital converter (ADC) designed for sensor interface and instrumentation applications. The ADC consists of a second-order incremental modulator and three post-integrators. The total area of the ADC is 0.55 square mm, with 0.53 square mm for analog modulator and 0.02 square mm for digital filter.

Good Practice: Maintain a Checklist

Design Review Checklist (Digital) 1. Design and verification diagram of the circuit architecture with various design Design Review Checklist (AMS) all modules and the top level design Detailed schematics and description emphasizing on the critical design st on design top passing parameters/modules. A summary of the circuit architecture with various design st on design top passing for a stream of inputs parameters is needed. Realistic testbench for sensitive circuits (high speed signals/single-ended analog ting all state (all registers and memories) via wishbone on caravel passing circuits/analog circuit that shares supply with switching elements, etc.). In this case, be careful about the supply network in the simulation (add bondwire model st exercised via wishbone only through software running to VDD and GND). est exercised through software running on caravel and ☐ Monte Carlo simulation for any circuit that needs precision, i.e. the reference voltage of comparator/current mirrors/resistor ratio etc. ☐ Test circuits have to be verified extensively. Any buffer/amplifier needed? digital-flow) sitive slack ☐ Use multiple VDD/GND pads (if available) to reduce the bonding parasitic. sitive slack with some margin ☐ Power distribution network (IR drop check), place decap/bypass cap at empty C has no violations spaces to reduce ripple etc. nnectivity has no violations ☐ Critical signal routing has to consider the routing parasitic (parasitic capacitance/resistance) in all corners (best, typical, worst) in PrimeTime (with ☐ Signal pad selection. If you want to measure precisely what the voltage/current is, you need a plain metal pad without any I/O circuits in it, and you will also need in all corners (best, typical, worst) in PrimeTime (with to be responsible for the ESD of it. Use analog_io if your signal speed is higher than 50 MHz or >3.3V or negative voltage. cs). Must have positive slack. 3. Testing and demonstration ☐ Back-up plans for critical test circuits/signals. For example, leave the option of being able to force an external signal into the chip if some block didn't work (usually a clock signal/reference/bias etc.). all SRAMs, DFFRAMs are connected to power and 4. System integration ☐ All the current bias signals for submodules should be locally re-generated with First run without SDF annotation then run with SDF one current source unless otherwise justified. ☐ To avoid power distribution network oscillation, use current sources with ation test on design top passing diode-connected transistors and bypass capacitors to provide low impedance d power targets ☐ The harness provides around [0:127] independent IO controls through the generation with openlane on-chip Logic Analyzer. If you have more control bits than this, build shift registers to accommodate the extras.

https://docs.google.com/document/d/1 4fVJJB9oHs8LzoYUo322H58PTyj044 MYgDIjb1f664o/edit

☐ DRC clean

LVS clean at the system level



https://www.youtube.com/watch?v=aBDJQ9NYTEU